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Reliability Test Summary

RTS No: 1193

Device Family: MOSFET - TH
Package: EP3 & TO220
Date From: 10/05/2007
Date To: 01/05/2008

Environmental Trial Data

Trial Type	Specification	Lots	Devices Tested	Devices Failed	Cumulative Hours	% Failures
CS (Cold Store)	JESD22-A119	3	135	0	136080	0.000
HS (Hot Store)	JESD22-A103	4	212	0	267120	0.000
PCLV (Pre-conditioned Autoclave)	JESD22-A102	2	154	0	14784	0.000
PTC (Pre-conditioned Temperature Cycle Air to Air)	JESD22-A104	2	154	0	155232	0.000
PTHB (Pre-conditioned Temperature Humidity + Bias)	JESD22-A101	1	77	0	77616	0.000
RSHD (Resistance to Solder Heat Dip)	JESD22-B106	3	135	0	135	0.000
Solderability (Post Hot Store)	IEC68-2-20	2	90	0	90	0.000

Electrical Stress Trials

Electrical Trial Type: **HTGB (High Temperature Gate Bias - JESD22-A108)**
Service Temperature (Deg C): 55
Ambient Temperature (Deg C): 150
Activation Energy (eV): 0.9
Confidence Level (%): 60

Actual Device Hours: 122976
Equivalent Device Hours: 1.565E+08
Lots: 2
Number of Devices Tested: 122
Number of Devices Failed: 0

Mean Time To Failure (Hours): 1.708E+08
Failure Rate FITs: 5.8540
Failure Rate %/1000 Hours: 5.854E-04

David Fitton
Quality Engineer